

Recursive Self-Correction Discrete Fourier Transform and application to impedance measurement

Liu, Ji-Gou; Schönecker, Andreas; Frühauf, Uwe BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 109-112: ill

System modelling and measurement under the view of design of testability and fault diagnosis of analog circuits

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Testability-based parameter measurement of analog measuring circuits in the frequency domain

Liu, Ji-Gou; Frühauf, Uwe BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 329-332: ill